

Docket No. 217868US2S/hc

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

IN RE APPLICATION OF: Hideaki HAYASHI, et al.

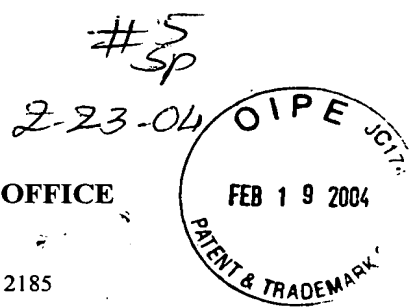
SERIAL NO: 10/028,788

GAU: 2185

FILED: December 28, 2001

EXAMINER:

FOR: APPARATUS MANAGEMENT METHOD, APPARATUS MANAGEMENT SYSTEM, AND APPARATUS MANAGEMENT PROGRAM PRODUCT



**INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97**

COMMISSIONER FOR PATENTS  
ALEXANDRIA, VIRGINIA 22313

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SIR:

FEB 20 2004

Applicant(s) wish to disclose the following information.

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**REFERENCES**

- ☒ The applicant(s) wish to make of record the references cited in the attached European Search Report listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

**RELATED CASES**

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

**CERTIFICATION**

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

**DEPOSIT ACCOUNT**

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,  
MAIER & NEUSTADT, P.C.

*Joseph A. Scafetta, Jr.*  
Marvin J. Spivak

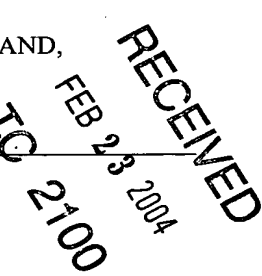
Registration No. 24,913

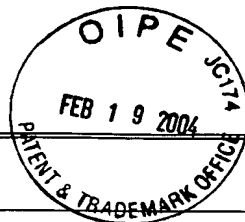
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Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.  
217868US2SSERIAL NO.  
10/028,788

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT  
Hideaki HAYASHI, et al.FILING DATE  
December 28, 2001GROUP  
2185

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	R. C. LEACHMAN, Advanced Semiconductor Manufacturing Conference, XP-010153305, pages 115-126, "CLOSED-LOOP MEASUREMENT OF EQUIPMENT EFFICIENCY AND EQUIPMENT CAPACITY", November 13, 1995				
	AX	R. S. GUO, et al., Semiconductor Manufacturing Technology, XP-010309544, pages 111-123, "A REAL-TIME EQUIPMENT MONITORING AND FAULT DETECTION SYSTEM", June 16, 1998				
	AY	P. DISESSA, et al., Advanced Semiconductor Manufacturing Conference, XP-010066371, pages 3-6, "AN ANALYTICAL APPROACH TO IMPROVING EQUIPMENT PRODUCTIVITY", September 30, 1992				
	AZ				<input type="checkbox"/> Additional References sheet(s) attached	

Examiner

Date Considered

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.